

In the Specification:

Please replace the paragraph beginning on page 8, line 7, with the following rewritten paragraph:

The prescribed amount by which the optimum write power is increased may be set in a vicinity of a difference between the optimum write power of the user track and the optimum write power of the write test track which are known in advance. Alternatively, the write power may be increased by a write retry process, so as to increase the optimum write power ~~may by~~ an ~~amounting amount~~ corresponding to this increase. Accordingly, the optimum write power can also be used to confirm the amount of signal leak from the adjacent tracks at the user track on which the user data is actually written.

Please replace the paragraph beginning on page 8, line 19, with the following rewritten paragraph:

The conventional test write process is carried out to obtain the optimum write power, and the approximately U-shaped curve of the write power versus the read error rate is detected by measuring the write power versus the read error rate on the test track. In the present invention, the center of the approximately U-shaped curve is regarded as the optimum write power, and a power immediately before the error rate begins to become large as the ~~write~~ write power is reduced with respect to the optimum write power is stored as a minimum write power. In addition, in a case where the data is recorded by increasing the write power by a prescribed amount and the width of the approximately U-shaped curve

when the optimum tracking target position is obtained is narrower than a prescribed width or, the error rate does not become less than or equal to a prescribed error rate, it is possible to carry out an operation of making the measurement again by reducing the optimum write power, writing the data at the write power which is increased by a prescribed amount with respect to the reduced optimum write power and making the measurement. The optimum write power may be reduced to the minimum write power obtained by the test write process. On the other hand, if the width of the approximately U-shaped curve is too wide compared to the prescribed width, the prescribed amount by which the write power is increased when writing the data on the adjacent tracks is further increased when writing the data, so as to make the measurement again.

Please replace the paragraph beginning on page 13, line 31, with the following rewritten paragraph:

FIG. 1 is a system block diagram showing the structure of a first embodiment of the storage apparatus according to the present invention. As shown in FIG. 1, the optical disk unit generally includes a control unit 110 and an enclosure 111. The control unit 110 includes a microprocessor unit (MPU) 112 which generally controls the operation of the optical disk unit, an interface 117 which exchanges commands and data between a host unit (not shown), an optical disk controller (ODC) 114 which carries out processes required to read and write data with respect to an optical disk (not shown), a digital signal processor (DSP) 116, and a memory 118. The memory 118 is used in common by the MPU 112, the

ODC 114 and the interface ~~114~~117, and for example, includes a dynamic random access memory (DRAM), a nonvolatile memory which stores control programs and flag information, or the like. A crystal oscillator 3101 is coupled to the MPU 112.